

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10758828	LEMAY ET AL.
	Examiner	Art Unit
	Lee, Benjamin W	3709

SEARCHED

Class	Subclass	Date	Examiner
463	24, 29, 34	12-7-2006	BWL
345	547-549	12-7-2006	BWL
463	24,29,34 (updated)	05/23/2007	BWL
345	547-549 (updated)	05/23/2007	BWL

SEARCH NOTES

Search Notes	Date	Examiner
Inventor Name Search	12-7-2006	BWL
Assignee Search	12-7-2006	BWL
Consulted with Kim Nguyen, CIs. 463, 345	12-5-2006	BWL
PLUS Search	12-4-2006	BWL
East Text Search (see attached "Search History")	12-8-2006	BWL
Backward/Forward Search	12-8-2006	BWL
EAST Text Search (see attached "Search History")	05/23/2007	BWL

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner